

**Search Notes**

Application/Control No.

10/697,762

Examiner

Toan M. Le

Applicant(s)/Patent under  
Reexamination

ANDOH ET AL.

Art Unit

2863

**SEARCHED**

Class	Subclass	Date	Examiner
702	196	3/28/2005	TL
702	179	3/29/2005	TL
702	199	3/29/2005	TL
435	6	3/29/2005	TL
702	19	3/29/2005	TL
702	20	3/29/2005	TL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
702	196	3/29/2005	TL
702	199	3/29/2005	TL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Effective Dimension Reduction, Microarray	3/29/2005	TL
Effective Dimension Reduction, Sliced Inverse Regression	3/29/2005	TL
Statistical, SIR, EDR	3/29/2005	TL
East, Web, and NPL search		